

Application/Control No.	Applicant(s)/Patent under Reexamination	_
10/673,932	HU, TECK	
Examiner	Art Unit	_
Khai M. Nguyen	2617	

SEARCHED					
Class	Subclass	Date	Examiner		
see	previous		KN		
	=				
			-		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	·				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East (see attached)	4/14/2007	KN		
		i		
		-		